

Enhancement Mode N-Channel Power MOSFET

PDFN3X3/NMOS/20V/ \pm 12V/0.75V/70A/2.5m Ω

Rev1.1





20V, 2.5mΩ, 70A, N-Channel MOSFET

1.Features

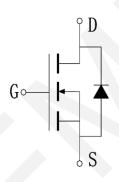
- ◆ 20V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±12V
- ♦ 100% RG Tested
- ◆ 100% UIS Tested

2.Applications

- Power Switching Application
- Load Switching



V _{DS}	R _{DS(on)} Typ.	I _D Max.	
20V	2.5mΩ @ 4.5V	704	
	3.5mΩ @ 2.5V	70A	



Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WP2070KP3	WP2070KP3	PDFN3X3	5,000	50,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V _{DSS}	20	V
Gate to Source Voltage	V _{GSS}	±12	V
Drain Current (DC)	l _D	70	А
Drain Current (Pulse), PW≤300μs	I _{DP}	280	А
Total Dissipation	P _D	83	W
Avalanche Energy, Single Pulsed	E _{AS}	182.25	mJ
Junction Temperature	Tj	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Junction to Case	Rejc	1.8	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

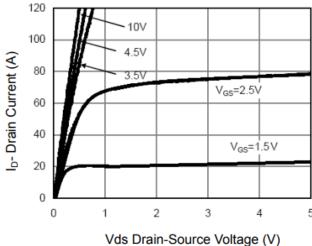
6.Electrical Characteristics at Ta=25°C (Note 3)

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A$, $V_{GS} = 0 V$	20	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} =20V, V _{GS} = 0V	-		1	μΑ
Gate to Source Leakage Current	Igss	$V_{GS} = \pm 12V, V_{DS} = 0V$	ı	-	±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	V _{DS} =V _{GS} , I _{DS} =250µA	0.4	0.75	1.2	V
Static Drain to Source On-State	Б	I _D =20A, V _{GS} = 4.5V	1	2.5	3.1	mΩ
Resistance	R _{DS(on)}	I _D = 10A, V _{GS} = 2.5V	-	3.5	5.1	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,	-	4073	-	pF
Output Capacitance	Coss	V _{DS} =10V,	-	484	-	pF
Reverse Transfer Capacitance	Crss	Frequency=1.0MHz	-	426	-	pF
Turn-ON Delay Time	t _{d(on)}		ı	6	-	ns
Rise Time	tr	$V_{DD} = 20V, R_L = 1\Omega,$	-	4	-	ns
Turn-OFF Delay Time	$t_{\sf d(off)}$	$V_{GS} = 10V, I_{D} = 30A,$ $R_{GEN} = 3\Omega$	-	31	-	ns
Fall Time	t _f		1	5	-	ns
	Qg	V _{DS} =20V, V _{GS} = 10V,	-	15	-	nC
Total Gate Charge	Qgs		-	3	-	nC
	Q _{gd}	I _D =30A	-	4	-	nC
Diode Forward Voltage	V_{FSD}	I _S =30A, V _{GS} = 0V	-	-	1.2	V

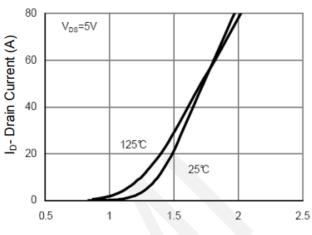
Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



7. Typical electrical and thermal characteristics



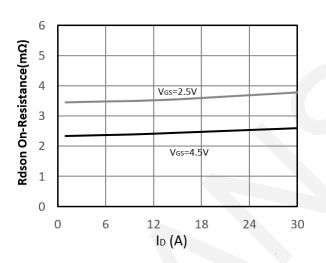
vus Diain-Source voltage (v)



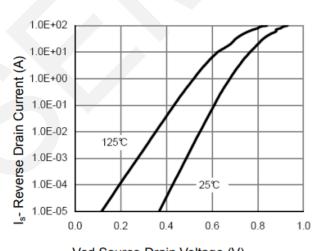
Vgs Gate-Source Voltage (V)

Typical Transfer Characteristics

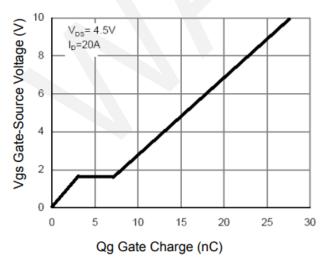
Output Characteristics



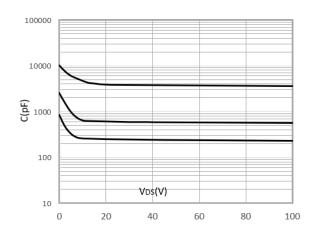
On-resistance vs. Drain Current



Vsd Source-Drain Voltage (V)
Body Diode Characteristics

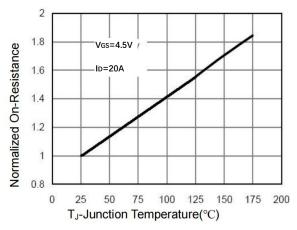


Gate Charge Characteristics



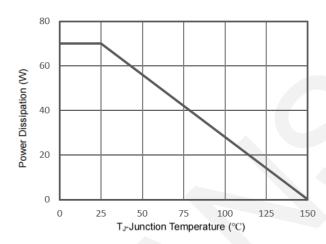
Capacitance Characteristics



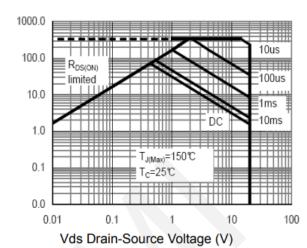


Normalized on Resistance vs.

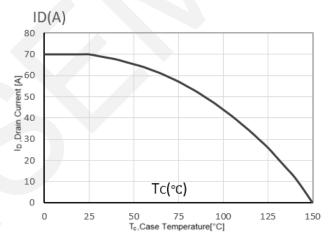
Junction Temperature



Power De-rating

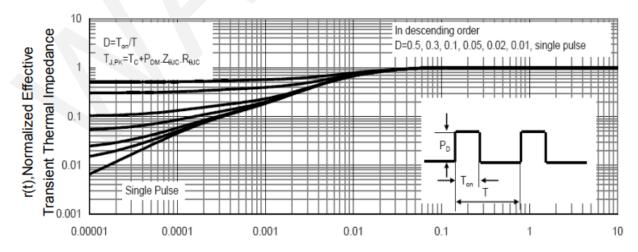


Maximum Safe Operating Area



Maximum Continuous Drain Current vs.

Case Temperature



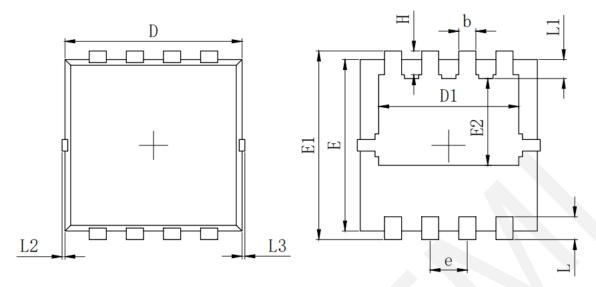
Ip- Drain Current (A)

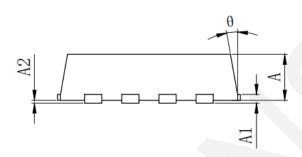
Square Wave Pluse Duration(sec)

Maximum Effective Transient Thermal Impedance, Junction-to-Case



8.Package Dimensions





SYMBOL		MILLIMETER	
SIMDUL	MIN	Тур.	MAX
A	0. 700	0.800	0.900
A1		0. 152 REF.	
A2		0~0.05	
D	3.000	3. 100	3. 200
D1	2. 300	2. 450	2.600
Е	2. 900	3.000	3. 100
E1	3. 150	3. 300	3.450
E2	1. 320	1.520	1.720
b	0. 200	0.300	0.400
e	0. 550	0.650	0.750
L	0.300	0.400	0.500
L1	0. 180	0.330	0.480
L2	0~0.100		
L3	0~0. 100		
Н	0. 315	0. 415	0.515
θ	8°	10°	12°



9. Important Notice

WAN SEMICONDUCTOR (NINGBO) CO.,LTD reserves the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services and to discontinue any product or service. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to WANSEMI's terms and conditions of sale supplied at the time of order acknowledgment.

WANSEMI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in WANSEMI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent WANSEMI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

WANSEMI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using WANSEMI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

No WANSEMI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Unless WANSEMI has specifically designated certain components which meet ISO/TS16949 requirements, mainly for automotive use, WANSEMI will not be responsible for any failure of such components to meet such requirements.